

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				2 *****	
				3 *	
				4 *            Zvector E6 instruction tests for VRI-f encoded:	
				5 *	
				6 *            E670 VPKZR   - VECTOR PACK ZONED REGISTER	
				7 *	
				8 *            James Wekel June 2024	
				9 *****	
				10	
				11 *****	
				12 *	
				13 *            basic instruction tests	
				14 *	
				15 *****	
				16 *    This program tests proper functioning of the z/arch E6 VRI-f vector	
				17 *    pack zoned register instruction. Exceptions are not tested.	
				18 *	
				19 *    PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch	
				20 *    obvious coding errors. None of the tests are thorough. They are	
				21 *    NOT designed to test all aspects of any of the instructions.	
				22 *	
				23 *****	
				24 *	
				25 *    *Testcase VECTOR E6 VPKZR: packed zoned register instruction	
				26 *    *	
				27 *    *    Zvector E6 tests for VRI-f encoded pack instructions:	
				28 *    *	
				29 *    *    E670 VPKZR   - VECTOR PACK ZONED REGISTER VPKZR	
				30 *    *	
				31 *    *    # -----	
				32 *    *    #    This tests only the basic function of the instruction.	
				33 *    *    #    Exceptions are NOT tested.	
				34 *    *    # -----	
				35 *    *	
				36 *    main size        2	
				37 *    numcpu           1	
				38 *    sysclear	
				39 *    archlvl          z/Arch	
				40 *	
				41 *    loadcore        "\$(testpath)/zvector-e6-06-VPKZR.core" 0x0	
				42 *	
				43 *    diag8cmd        enable        # (needed for messages to Hercules console)	
				44 *    runtest          2	
				45 *    diag8cmd        disable       # (reset back to default)	
				46 *	
				47 *    *Done	
				48 *****	
00000000		00000000	000019D7	50 ZVE6TST    START 0	
		00000000		51            USING ZVE6TST, R0	Low core addressability
				52	
		00000140	00000000	53 SVOLDPSW EQU    ZVE6TST+X' 140'	z/Arch Supervisor call old PSW
00000000		00000000	000001A0	55            ORG    ZVE6TST+X' 1A0'	z/Architecture RESTART PSW



[illegible]



LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						138	*****
						139	* cc was not as expected
						140	*****
0000026E	E310	0001	0082	0000026E	00000001	141	CCMSG EQU *
00000274	E310	5008	0076		00000001	142	XG R1, R1
0000027A	5410	82B0			00000008	143	LB R1, M5 M5 has CS bit
0000027E	4780	8052			000004B0	144	N R1, =F' 1' get CS (CC set) bit
					00000252	145	BZ TESTREST ignore if not set
						146	*
						147	* extract CC extracted PSW
						148	*
00000282	5810	8EE4			000010E4	149	L R1, CCPSW
00000286	8810	000C			0000000C	150	SRL R1, 12
0000028A	5410	82B4			000004B4	151	N R1, =XL4' 3'
0000028E	4210	8EEC			000010EC	152	STC R1, CCFOUND save cc
						153	*
						154	* FILL IN MESSAGE
						155	*
00000292	4820	5004			00000004	156	LH R2, TNUM get test number and convert
00000296	4E20	8ED1			000010D1	157	CVD R2, DECNUM
0000029A	D211	8EBB	8EA5	000010BB	000010A5	158	MVC PRT3, EDIT
000002A0	DE11	8EBB	8ED1	000010BB	000010D1	159	ED PRT3, DECNUM
000002A6	D202	8E60	8EC8	00001060	000010C8	160	MVC CCPRTNUM(3), PRT3+13 fill in message with test #
						161	
000002AC	D207	8E7D	5014	0000107D	00000014	162	MVC CCPRTNAME, OPNAME fill in message with instruction
						163	
000002B2	B982	0022				164	XGR R2, R2 get CC as U8
000002B6	4320	5009			00000009	165	IC R2, CC
000002BA	4E20	8ED1			000010D1	166	CVD R2, DECNUM and convert
000002BE	D211	8EBB	8EA5	000010BB	000010A5	167	MVC PRT3, EDIT
000002C4	DE11	8EBB	8ED1	000010BB	000010D1	168	ED PRT3, DECNUM
000002CA	D200	8E93	8ECA	00001093	000010CA	169	MVC CCPRTEXP(1), PRT3+15 fill in message with CC field
						170	
000002D0	B982	0022				171	XGR R2, R2 get CCFOUND as U8
000002D4	4320	8EEC			000010EC	172	IC R2, CCFOUND
000002D8	4E20	8ED1			000010D1	173	CVD R2, DECNUM and convert
000002DC	D211	8EBB	8EA5	000010BB	000010A5	174	MVC PRT3, EDIT
000002E2	DE11	8EBB	8ED1	000010BB	000010D1	175	ED PRT3, DECNUM
000002E8	D200	8EA3	8ECA	000010A3	000010CA	176	MVC CCPRTGOT(1), PRT3+15 fill in message with ccfound
						177	
000002EE	4100	0055			00000055	178	LA R0, CCPRTLNG message length
000002F2	4110	8E50			00001050	179	LA R1, CCPRTLNE messagfe address
000002F6	45F0	8184			00000384	180	BAL R15, RPTERROR
						181	
000002FA	47F0	8166			00000366	182	B FAILCONT

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						184 *****	
						185 * result not as expected:	
						186 * issue message with test number, instruction under test	
						187 * and instruction m3	
						188 *****	
				000002FE	00000001	189 FAILMSG EQU *	
000002FE	4820	5004			00000004	190 LH R2, TNUM	get test number and convert
00000302	4E20	8ED1			000010D1	191 CVD R2, DECNUM	
00000306	D211	8EBB 8EA5		000010BB	000010A5	192 MWC PRT3, EDIT	
0000030C	DE11	8EBB 8ED1		000010BB	000010D1	193 ED PRT3, DECNUM	
00000312	D202	8E14 8EC8		00001014	000010C8	194 MWC PRTNUM(3), PRT3+13	fill in message with test #
						195	
00000318	D207	8E2F 5014		0000102F	00000014	196 MWC PRTNAME, OPNAME	fill in message with instruction
						197	
0000031E	B982	0022				198 XGR R2, R2	get i4 as U8
00000322	4320	5007			00000007	199 IC R2, I4	
00000326	4E20	8ED1			000010D1	200 CVD R2, DECNUM	and convert
0000032A	D211	8EBB 8EA5		000010BB	000010A5	201 MWC PRT3, EDIT	
00000330	DE11	8EBB 8ED1		000010BB	000010D1	202 ED PRT3, DECNUM	
00000336	D202	8E40 8EC8		00001040	000010C8	203 MWC PRTI4(3), PRT3+13	fill in message with i4 field
						204	
0000033C	B982	0022				205 XGR R2, R2	get m5 as U8
00000340	4320	5008			00000008	206 IC R2, M5	and convert
00000344	4E20	8ED1			000010D1	207 CVD R2, DECNUM	
00000348	D211	8EBB 8EA5		000010BB	000010A5	208 MWC PRT3, EDIT	
0000034E	DE11	8EBB 8ED1		000010BB	000010D1	209 ED PRT3, DECNUM	
00000354	D201	8E4D 8EC9		0000104D	000010C9	210 MWC PRTM5(2), PRT3+14	fill in message with m5 field
						211	
0000035A	4100	004C			0000004C	212 LA R0, PRTLNG	message length
0000035E	4110	8E04			00001004	213 LA R1, PRTLNE	messagfe address
00000362	45F0	8184			00000384	214 BAL R15, RPTERROR	
						216 *****	
						217 * continue after a failed test	
						218 *****	
				00000366	00000001	219 FAILCONT EQU *	
00000366	5800	82B0			000004B0	220 L R0, =F' 1'	set GLOBAL failed test indicator
0000036A	5000	8E00			00001000	221 ST R0, FAILED	
						222	
0000036E	41C0	C004			00000004	223 LA R12, 4(0, R12)	next test address
00000372	47F0	802A			0000022A	224 B NEXTE6	
						226 *****	
						227 * end of testing; set ending psw	
						228 *****	
				00000376	00000001	229 ENDTEST EQU *	
00000376	5810	8E00			00001000	230 L R1, FAILED	did a test fail?
0000037A	1211					231 LTR R1, R1	
0000037C	4780	8288			00000488	232 BZ EOJ	No, exit
00000380	47F0	82A0			000004A0	233 B FAILTEST	Yes, exit with BAD PSW
						234	









LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				295	*****
				296	*            Normal completion or Abnormal termination PSWs
				297	*****
00000478	00020001 80000000			299	E0JPSW    DC    0D' 0' , X' 0002000180000000' , AD(0)
00000488	B2B2 8278		00000478	301	E0J            LPSWE E0JPSW            Normal completion
00000490	00020001 80000000			303	FAILPSW    DC    0D' 0' , X' 0002000180000000' , AD(X' BAD' )
000004A0	B2B2 8290		00000490	305	FAILTEST LPSWE FAILPSW            Abnormal termination
				307	*****
				308	*            Working Storage
				309	*****
000004A4	00000000			311	CTLRO       DS    F            CRO
000004A8	00000000			312	DS    F
				313	
000004AC	00001988			314	E6TADR    DC    A(E6TESTS)            address of E6 test table
000004B0				316	LTORG ,            Literals pool
000004B0	00000001			317	=F' 1'
000004B4	00000003			318	=XL4' 3'
000004B8	0000			319	=H' 0'
000004BA	005F			320	=AL2(L' MSGMSG)
				321	
				322	*            some constants
				323	
	00000400	00000001		324	K            EQU    1024            One KB
	00001000	00000001		325	PAGE        EQU    (4*K)            Size of one page
	00010000	00000001		326	K64         EQU    (64*K)            64 KB
	00100000	00000001		327	MB          EQU    (K*K)            1 MB
				328	
	AABBCCDD	00000001		329	REG2PATT EQU    X' AABBCCDD'            Polluted Register pattern
	000000DD	00000001		330	REG2LOW EQU            X' DD'            (last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				332 *=====
				333 *
				334 *    NOTE: start data on an address that is easy to display
				335 *                within Hercules
				336 *
				337 *=====
				338
000004BC		000004BC	00001000	339                ORG    ZVE6TST+X' 1000'
00001000	00000000			340 FAILED    DC    F' 0'                        some test failed?
				342 *****
				343 *                TEST failed : result messgae
				344 *****
				345 *
				346 *                failed message and associated editting
				347 *
00001004	40404040	40404040		348 PRTLIN    DC    C'                Test # '
00001014	A7A7A7			349 PRTNUM    DC    C' xxx'
00001017	40868189	93858440		350                DC    C' failed for instruction '
0000102F	A7A7A7A7	A7A7A7A7		351 PRTNAME    DC    CL8' xxxxxxxxx'
00001037	40A689A3	884089F4		352                DC    C' with i4='
00001040	A7A7A7			353 PRTI4      DC    C' xxx'
00001043	6B			354                DC    C' ,'
00001044	40A689A3	884094F5		355                DC    C' with m5='
0000104D	A7A7			356 PRTM5      DC    C' xx'
0000104F	4B			357                DC    C' .'
		0000004C	00000001	358 PRTLNG    EQU    *- PRTLIN
				360 *****
				361 *                TEST failed : CC message
				362 *****
				363 *
				364 *                failed message and associated editting
				365 *
00001050	40404040	40404040		366 CCPRTLIN    DC    C'                Test # '
00001060	A7A7A7			367 CCPRTNUM    DC    C' xxx'
00001063	40A69996	95874083		368                DC    c' wrong cc for instruction '
0000107D	A7A7A7A7	A7A7A7A7		369 CCPRTNAME    DC    CL8' xxxxxxxxx'
00001085	4085A797	8583A385		370                DC    C' expected: cc='
00001093	A7			371 CCPRTEXP    DC    C' x'
00001094	6B			372                DC    C' ,'
00001095	40998583	8589A585		373                DC    C' received: cc='
000010A3	A7			374 CCPRTGOT    DC    C' x'
000010A4	4B			375                DC    C' .'
		00000055	00000001	376 CCPRTLNG    EQU    *- CCPRTLIN





LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				433 *****
				434 * <b>Macros to help build test tables</b>
				435 *-----
				436 * <b>VRI_F Macro to help build test tables</b>
				437 *****
				438 <b>MACRO</b>
				439 <b>VRI_F &amp;INST, &amp;I4, &amp;M5, &amp;CC</b>
				440 . * <b>&amp;INST - VRI-f instruction under test</b>
				441 . * <b>&amp;i4 - i4 field</b>
				442 . * <b>&amp;m5 - m5 field</b>
				443 . * <b>&amp;CC - expected CC</b>
				444 . *
				445 <b>LCLA &amp;XCC(4) &amp;CC has mask values for FAILED condition codes</b>
				446 &XCC(1) <b>SETA 7               CC != 0</b>
				447 &XCC(2) <b>SETA 11           CC != 1</b>
				448 &XCC(3) <b>SETA 13           CC != 2</b>
				449 &XCC(4) <b>SETA 14           CC != 3</b>
				450
				451 <b>GBLA &amp;TNUM</b>
				452 &TNUM <b>SETA &amp;TNUM+1</b>
				453
				454 <b>DS    OFD</b>
				455 <b>USING *, R5               base for test data and test routine</b>
				456
				457 T&TNUM <b>DC    A(X&amp;TNUM)       address of test routine</b>
				458 <b>DC    H' &amp;TNUM       test number</b>
				459 <b>DC    X' 00'</b>
				460 <b>DC    HL1' &amp;I4'       i4</b>
				461 <b>DC    HL1' &amp;M5'       m5</b>
				462 <b>DC    HL1' &amp;CC'       cc</b>
				463 <b>DC    HL1' &amp;XCC(&amp;CC+1)'   cc failed mask</b>
				464 V2_&TNUM <b>DC    A(RE&amp;TNUM+16)   address of v2: 16-byte zoned decimal</b>
				465 V3_&TNUM <b>DC    A(RE&amp;TNUM+32)   address of v3: 16-byte zoned decimal</b>
				466 <b>DC    CL8' &amp;INST'       instruction name</b>
				467 <b>DC    A(16)           result length</b>
				468 REA&TNUM <b>DC    A(RE&amp;TNUM)       result address</b>
				469 . *
				470 * <b>INSTRUCTION UNDER TEST ROUTINE</b>
				471 X&TNUM <b>DS    OF</b>
				472 <b>L     R2, V2_&amp;TNUM       get v2</b>
				473 <b>VL    V2, 0(R2)</b>
				474
				475 <b>L     R2, V3_&amp;TNUM       get v3</b>
				476 <b>VL    V3, 0(R2)</b>
				477
				478 <b>&amp;INST V1, V2, V3, &amp;I4, &amp;M5   test instruction</b>
				479
				480 <b>VST   V1, V10OUTPUT       save result</b>
				481 <b>EPSW   R2, R0           exptrect psw</b>
				482 <b>ST     R2, CCPSW       to save CC</b>
				483 <b>BR     R11           return</b>
				484
				485 RE&TNUM <b>DC    OF</b>
				486 <b>DROP   R5</b>
				487
				488 <b>MEND</b>

490	*****		
491	* PTTABLE Macro to generate table of pointers to individual tests		
492	*****		
493			
494	MACRO		
495	PTTABLE		
496		GBLA	&TNUM
497		LCLA	&CUR
498	&CUR	SETA	1
499	. *		
500	TTABLE	DS	OF
501	. LOOP	ANOP	
502	. *		
503		DC	A(T&CUR) address of test
504	. *		
505	&CUR	SETA	&CUR+1
506		AIF	(&CUR LE &TNUM) . LOOP
507	*		
508		DC	A(0) END OF TABLE
509		DC	A(0)
510	. *		
511	MEND		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				513 *****	
				514 * E6 VRI_F tests	
				515 *****	
00001180		00000000	000019D7	516 ZVE6TST CSECT ,	
				517 DS 0F	
				519 PRINT DATA	
				520 *	
				521 * E670 VPKZR - VECTOR PACK ZONED REGISTER	
				522 *	
				523 * VRI_F instr,i4,m5,cc	
				524 * followed by	
				525 * v1 - 16 byte expected result	
				526 * v2 - 16 byte zoned decimal (operand)	
				527 * v3 - 16 byte zoned decimal (operand)	
				528	
				529 * -----	
				530 * VPKZR - VECTOR PACK ZONED REGISTER	
				531 * -----	
				532 * VPKZR simple + CC checks	
				533 *	i4=129(iom=1 & rdc=1)
				534 *	i4=132(iom=1 & rdc=4)
				535 *	i4=135(iom=1 & rdc=7)
				536 *	i4=142(iom=1 & rdc=14)
				537 *	i4=159(iom=1 & rdc=31)
00001180				538 VRI_F VPKZR, 159, 1, 2	
00001180				539+ DS 0FD	
00001180		00001180		540+ USING *,R5	base for test data and test routine
00001180	000011A4			541+T1 DC A(X1)	address of test routine
00001184	0001			542+ DC H' 1'	test number
00001186	00			543+ DC X' 00'	
00001187	9F			544+ DC HL1' 159'	i4
00001188	01			545+ DC HL1' 1'	m5
00001189	02			546+ DC HL1' 2'	cc
0000118A	0D			547+ DC HL1' 13'	cc failed mask
0000118C	000011E0			548+V2_1 DC A(RE1+16)	address of v2: 16-byte zoned decimal
00001190	000011F0			549+V3_1 DC A(RE1+32)	address of v3: 16-byte zoned decimal
00001194	E5D7D2E9 D9404040			550+ DC CL8' VPKZR'	instruction name
0000119C	00000010			551+ DC A(16)	result length
000011A0	000011D0			552+REA1 DC A(RE1)	result address
				553+*	INSTRUCTION UNDER TEST ROUTINE
000011A4				554+X1 DS 0F	
000011A4	5820 500C		0000118C	555+ L R2, V2_1	get v2
000011A8	E722 0000 0006		00000000	556+ VL V2, 0(R2)	
000011AE	5820 5010		00001190	557+ L R2, V3_1	get v3
000011B2	E732 0000 0006		00000000	558+ VL V3, 0(R2)	
000011B8	E612 3019 F070			559+ VPKZR V1, V2, V3, 159, 1	test instruction
000011BE	E710 8F00 000E		00001100	560+ VST V1, V10UTPUT	save result
000011C4	B98D 0020			561+ EPSW R2, R0	extract psw
000011C8	5020 8EE4		000010E4	562+ ST R2, CCPSW	to save CC
000011CC	07FB			563+ BR R11	return
000011D0				564+RE1 DC 0F	
000011D0				565+ DROP R5	
000011D0	00000000 00000000			566 DC XL16' 000000000000000000000000000022C'	V1
000011D8	00000000 0000022C				



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000011E0	F0F0F0F0 F0F0F0F0			567	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
000011E8	F0F0F0F0 F0F0F0F0						
000011F0	F0F0F0F0 F0F0F0F0			568	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F2C2'	V3
000011F8	F0F0F0F0 F0F0F2C2						
				569			
00001200				570	VRI_F	VPKZR, 159, 1, 2	
00001200		00001200		571+	DS	OFD	
00001200				572+	USING	*, R5	base for test data and test routine
00001200	00001224			573+T2	DC	A(X2)	address of test routine
00001204	0002			574+	DC	H' 2'	test number
00001206	00			575+	DC	X' 00'	
00001207	9F			576+	DC	HL1' 159'	i4
00001208	01			577+	DC	HL1' 1'	m5
00001209	02			578+	DC	HL1' 2'	cc
0000120A	0D			579+	DC	HL1' 13'	cc failed mask
0000120C	00001260			580+V2_2	DC	A(RE2+16)	address of v2: 16-byte zoned decimal
00001210	00001270			581+V3_2	DC	A(RE2+32)	address of v3: 16-byte zoned decimal
00001214	E5D7D2E9 D9404040			582+	DC	CL8' VPKZR'	instruction name
0000121C	00000010			583+	DC	A(16)	result length
00001220	00001250			584+REA2	DC	A(RE2)	result address
				585+*			INSTRUCTION UNDER TEST ROUTINE
00001224				586+X2	DS	OF	
00001224	5820 900C		0000120C	587+	L	R2, V2_2	get v2
00001228	E722 0000 0006		00000000	588+	VL	V2, 0(R2)	
0000122E	5820 9010		00001210	589+	L	R2, V3_2	get v3
00001232	E732 0000 0006		00000000	590+	VL	V3, 0(R2)	
00001238	E612 3019 F070			591+	VPKZR	V1, V2, V3, 159, 1	test instruction
0000123E	E710 8F00 000E		00001100	592+	VST	V1, V10UTPUT	save result
00001244	B98D 0020			593+	EPSW	R2, R0	exptract psw
00001248	5020 8EE4		000010E4	594+	ST	R2, CCPSW	to save CC
0000124C	07FB			595+	BR	R11	return
00001250				596+RE2	DC	OF	
00001250				597+	DROP	R5	
00001250	12300000 00000000			598	DC	XL16' 12300000000000000000000000000000122C'	V1
00001258	00000000 0000122C						
00001260	F0F1F2F3 F0F0F0F0			599	DC	XL16' F0F1F2F3F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001268	F0F0F0F0 F0F0F0F0						
00001270	F0F0F0F0 F0F0F0F0			600	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F1F2C2'	V3
00001278	F0F0F0F0 F0F1F2C2						
				601			
00001280				602	VRI_F	VPKZR, 159, 1, 1	
00001280		00001280		603+	DS	OFD	
00001280				604+	USING	*, R5	base for test data and test routine
00001280	000012A4			605+T3	DC	A(X3)	address of test routine
00001284	0003			606+	DC	H' 3'	test number
00001286	00			607+	DC	X' 00'	
00001287	9F			608+	DC	HL1' 159'	i4
00001288	01			609+	DC	HL1' 1'	m5
00001289	01			610+	DC	HL1' 1'	cc
0000128A	0B			611+	DC	HL1' 11'	cc failed mask
0000128C	000012E0			612+V2_3	DC	A(RE3+16)	address of v2: 16-byte zoned decimal
00001290	000012F0			613+V3_3	DC	A(RE3+32)	address of v3: 16-byte zoned decimal
00001294	E5D7D2E9 D9404040			614+	DC	CL8' VPKZR'	instruction name
0000129C	00000010			615+	DC	A(16)	result length
000012A0	000012D0			616+REA3	DC	A(RE3)	result address
				617+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000012A4				618+X3	DS	0F	
000012A4	5820 500C		0000128C	619+	L	R2, V2_3	get v2
000012A8	E722 0000 0006		00000000	620+	VL	V2, 0(R2)	
000012AE	5820 5010		00001290	621+	L	R2, V3_3	get v3
000012B2	E732 0000 0006		00000000	622+	VL	V3, 0(R2)	
000012B8	E612 3019 F070			623+	VPKZR	V1, V2, V3, 159, 1	test instruction
000012BE	E710 8F00 000E		00001100	624+	VST	V1, V10UTPUT	save result
000012C4	B98D 0020			625+	EPSW	R2, R0	exptract psw
000012C8	5020 8EE4		000010E4	626+	ST	R2, CCPSW	to save CC
000012CC	07FB			627+	BR	R11	return
000012D0				628+RE3	DC	0F	
000012D0				629+	DROP	R5	
000012D0	98700000 00000000			630	DC	XL16' 98700000000000000000000000000000123D'	V1
000012D8	00000000 0000123D						
000012E0	F0F9F8F7 F0F0F0F0			631	DC	XL16' F0F9F8F7F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
000012E8	F0F0F0F0 F0F0F0F0						
000012F0	F0F0F0F0 F0F0F0F0			632	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F1F2D3'	V3
000012F8	F0F0F0F0 F0F1F2D3						
				633			
				634	VRI_F	VPKZR, 159, 1, 3	(overflow; 1st zone is not 0 )
00001300				635+	DS	0FD	
00001300		00001300		636+	USING	*, R5	base for test data and test routine
00001300	00001324			637+T4	DC	A(X4)	address of test routine
00001304	0004			638+	DC	H' 4'	test number
00001306	00			639+	DC	X' 00'	
00001307	9F			640+	DC	HL1' 159'	i4
00001308	01			641+	DC	HL1' 1'	m5
00001309	03			642+	DC	HL1' 3'	cc
0000130A	0E			643+	DC	HL1' 14'	cc failed mask
0000130C	00001360			644+V2_4	DC	A(RE4+16)	address of v2: 16-byte zoned decimal
00001310	00001370			645+V3_4	DC	A(RE4+32)	address of v3: 16-byte zoned decimal
00001314	E5D7D2E9 D9404040			646+	DC	CL8' VPKZR'	instruction name
0000131C	00000010			647+	DC	A(16)	result length
00001320	00001350			648+REA4	DC	A(RE4)	result address
				649+*			INSTRUCTION UNDER TEST ROUTINE
00001324				650+X4	DS	0F	
00001324	5820 500C		0000130C	651+	L	R2, V2_4	get v2
00001328	E722 0000 0006		00000000	652+	VL	V2, 0(R2)	
0000132E	5820 5010		00001310	653+	L	R2, V3_4	get v3
00001332	E732 0000 0006		00000000	654+	VL	V3, 0(R2)	
00001338	E612 3019 F070			655+	VPKZR	V1, V2, V3, 159, 1	test instruction
0000133E	E710 8F00 000E		00001100	656+	VST	V1, V10UTPUT	save result
00001344	B98D 0020			657+	EPSW	R2, R0	exptract psw
00001348	5020 8EE4		000010E4	658+	ST	R2, CCPSW	to save CC
0000134C	07FB			659+	BR	R11	return
00001350				660+RE4	DC	0F	
00001350				661+	DROP	R5	
00001350	00000000 00000000			662	DC	XL16' 00000000000000000000000000000000123D'	V1
00001358	00000000 0000123D						
00001360	F9F0F0F0 F0F0F0F0			663	DC	XL16' F9F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001368	F0F0F0F0 F0F0F0F0						
00001370	F0F0F0F0 F0F0F0F0			664	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F1F2D3'	V3
00001378	F0F0F0F0 F0F1F2D3						
				665			
				666	VRI_F	VPKZR, 135, 1, 3	(overflow; rdc=7 )
00001380				667+	DS	0FD	



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001444	B98D 0020			721+	EPSW	R2, R0	exptract psw
00001448	5020 8EE4		000010E4	722+	ST	R2, CCPSW	to save CC
0000144C	07FB			723+	BR	R11	return
00001450				724+RE6	DC	0F	
00001450				725+	DROP	R5	
00001450	00000000 00000000			726	DC	XL16' 0000000000000000000000000000123D'	V1
00001458	00000000 0000123D						
00001460	F0F0F0F0 F0F0F0F0			727	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001468	F0F0F0F0 F0F0F0F0						
00001470	F0F0F0F0 F0F0F0F0			728	DC	XL16' F0F0F0F0F0F0F0F0F0F0F9F0F0F0F0F1F2D3'	V3
00001478	F9F0F0F0 F0F1F2D3						
				729			
00001480				730	VRI_F	VPKZR, 142, 1, 3	(overflow; rdc=14)
00001480		00001480		731+	DS	0FD	
00001480	000014A4			732+	USING	*, R5	base for test data and test routine
00001480	0007			733+T7	DC	A(X7)	address of test routine
00001484	00			734+	DC	H' 7'	test number
00001486	00			735+	DC	X' 00'	
00001487	8E			736+	DC	HL1' 142'	i4
00001488	01			737+	DC	HL1' 1'	m5
00001489	03			738+	DC	HL1' 3'	cc
0000148A	0E			739+	DC	HL1' 14'	cc failed mask
0000148C	000014E0			740+V2_7	DC	A(RE7+16)	address of v2: 16-byte zoned decimal
00001490	000014F0			741+V3_7	DC	A(RE7+32)	address of v3: 16-byte zoned decimal
00001494	E5D7D2E9 D9404040			742+	DC	CL8' VPKZR'	instruction name
0000149C	00000010			743+	DC	A(16)	result length
000014A0	000014D0			744+REA7	DC	A(RE7)	result address
				745+*			INSTRUCTION UNDER TEST ROUTINE
000014A4				746+X7	DS	0F	
000014A4	5820 500C		0000148C	747+	L	R2, V2_7	get v2
000014A8	E722 0000 0006		00000000	748+	VL	V2, 0(R2)	
000014AE	5820 5010		00001490	749+	L	R2, V3_7	get v3
000014B2	E732 0000 0006		00000000	750+	VL	V3, 0(R2)	
000014B8	E612 3018 E070			751+	VPKZR	V1, V2, V3, 142, 1	test instruction
000014BE	E710 8F00 000E		00001100	752+	VST	V1, V10UTPUT	save result
000014C4	B98D 0020			753+	EPSW	R2, R0	exptract psw
000014C8	5020 8EE4		000010E4	754+	ST	R2, CCPSW	to save CC
000014CC	07FB			755+	BR	R11	return
000014D0				756+RE7	DC	0F	
000014D0				757+	DROP	R5	
000014D0	00000000 00000000			758	DC	XL16' 00000000000000000000000090000123D'	V1
000014D8	00000009 0000123D						
000014E0	F0F0F0F0 F0F0F0F0			759	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F9'	V2
000014E8	F0F0F0F0 F0F0F0F9						
000014F0	F0F0F0F0 F0F0F0F0			760	DC	XL16' F0F0F0F0F0F0F0F0F0F0F9F0F0F0F0F1F2D3'	V3
000014F8	F9F0F0F0 F0F1F2D3						
				761			
				762	* m5 tests (note: cs is always 1)		
				763	*	m5=1	(nsv=0, nv=0, p1=0, cs=1)
				764	*	m5=3	(nsv=0, nv=0, p1=1, cs=1)
				765	*	m5=5	(nsv=0, nv=1, p1=0, cs=1)
				766	*	m5=7	(nsv=0, nv=1, p1=1, cs=1)
				767	*	m5=9	(nsv=1, nv=0, p1=0, cs=1)
				768	*	m5=11	(nsv=1, nv=0, p1=1, cs=1)
				769	*	m5=13	(nsv=1, nv=1, p1=0, cs=1)
				770	*	m5=15	(nsv=1, nv=1, p1=1, cs=1)



LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				771		
				772	VRI_F VPKZR, 159, 3, 2	
00001500				773+	DS OFD	
00001500		00001500		774+	USING *, R5	base for test data and test routine
00001500	00001524			775+T8	DC A(X8)	address of test routine
00001504	0008			776+	DC H' 8'	test number
00001506	00			777+	DC X' 00'	
00001507	9F			778+	DC HL1' 159'	i4
00001508	03			779+	DC HL1' 3'	m5
00001509	02			780+	DC HL1' 2'	cc
0000150A	0D			781+	DC HL1' 13'	cc failed mask
0000150C	00001560			782+V2_8	DC A(RE8+16)	address of v2: 16-byte zoned decimal
00001510	00001570			783+V3_8	DC A(RE8+32)	address of v3: 16-byte zoned decimal
00001514	E5D7D2E9 D9404040			784+	DC CL8' VPKZR'	instruction name
0000151C	00000010			785+	DC A(16)	result length
00001520	00001550			786+REA8	DC A(RE8)	result address
				787+*		INSTRUCTION UNDER TEST ROUTINE
00001524				788+X8	DS OF	
00001524	5820 500C		0000150C	789+	L R2, V2_8	get v2
00001528	E722 0000 0006		00000000	790+	VL V2, 0(R2)	
0000152E	5820 5010		00001510	791+	L R2, V3_8	get v3
00001532	E732 0000 0006		00000000	792+	VL V3, 0(R2)	
00001538	E612 3039 F070			793+	VPKZR V1, V2, V3, 159, 3	test instruction
0000153E	E710 8F00 000E		00001100	794+	VST V1, V10UTPUT	save result
00001544	B98D 0020			795+	EPSW R2, R0	exptract psw
00001548	5020 8EE4		000010E4	796+	ST R2, CCPSW	to save CC
0000154C	07FB			797+	BR R11	return
00001550				798+RE8	DC OF	
00001550				799+	DROP R5	
00001550	00000000 00000000			800	DC XL16' 0000000000000000000000000000000022F'	V1
00001558	00000000 0000022F					
00001560	F0F0F0F0 F0F0F0F0			801	DC XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001568	F0F0F0F0 F0F0F0F0					
00001570	F0F0F0F0 F0F0F0F0			802	DC XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F2C2'	V3
00001578	F0F0F0F0 F0F0F2C2					
				803		
				804	VRI_F VPKZR, 159, 3, 2	p1=1
00001580				805+	DS OFD	
00001580		00001580		806+	USING *, R5	base for test data and test routine
00001580	000015A4			807+T9	DC A(X9)	address of test routine
00001584	0009			808+	DC H' 9'	test number
00001586	00			809+	DC X' 00'	
00001587	9F			810+	DC HL1' 159'	i4
00001588	03			811+	DC HL1' 3'	m5
00001589	02			812+	DC HL1' 2'	cc
0000158A	0D			813+	DC HL1' 13'	cc failed mask
0000158C	000015E0			814+V2_9	DC A(RE9+16)	address of v2: 16-byte zoned decimal
00001590	000015F0			815+V3_9	DC A(RE9+32)	address of v3: 16-byte zoned decimal
00001594	E5D7D2E9 D9404040			816+	DC CL8' VPKZR'	instruction name
0000159C	00000010			817+	DC A(16)	result length
000015A0	000015D0			818+REA9	DC A(RE9)	result address
				819+*		INSTRUCTION UNDER TEST ROUTINE
000015A4				820+X9	DS OF	
000015A4	5820 500C		0000158C	821+	L R2, V2_9	get v2
000015A8	E722 0000 0006		00000000	822+	VL V2, 0(R2)	
000015AE	5820 5010		00001590	823+	L R2, V3_9	get v3



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001687	9F			874+	DC	HL1' 159'	i4
00001688	05			875+	DC	HL1' 5'	m5
00001689	03			876+	DC	HL1' 3'	cc
0000168A	0E			877+	DC	HL1' 14'	cc failed mask
0000168C	000016E0			878+V2_11	DC	A(RE11+16)	address of v2: 16-byte zoned decimal
00001690	000016F0			879+V3_11	DC	A(RE11+32)	address of v3: 16-byte zoned decimal
00001694	E5D7D2E9 D9404040			880+	DC	CL8' VPKZR'	instruction name
0000169C	00000010			881+	DC	A(16)	result length
000016A0	000016D0			882+REA11	DC	A(RE11)	result address
				883+*			INSTRUCTION UNDER TEST ROUTINE
000016A4				884+X11	DS	0F	
000016A4	5820 500C		0000168C	885+	L	R2, V2_11	get v2
000016A8	E722 0000 0006		00000000	886+	VL	V2, 0(R2)	
000016AE	5820 5010		00001690	887+	L	R2, V3_11	get v3
000016B2	E732 0000 0006		00000000	888+	VL	V3, 0(R2)	
000016B8	E612 3059 F070			889+	VPKZR	V1, V2, V3, 159, 5	test instruction
000016BE	E710 8F00 000E		00001100	890+	VST	V1, V10UTPUT	save result
000016C4	B98D 0020			891+	EPSW	R2, R0	exptract psw
000016C8	5020 8EE4		000010E4	892+	ST	R2, CCPSW	to save CC
000016CC	07FB			893+	BR	R11	return
000016D0				894+RE11	DC	0F	
000016D0				895+	DROP	R5	
000016D0	F0000000 00000000			896	DC	XL16' F00000000000000000000000000000229'	V1
000016D8	00000000 00000229						
000016E0	F0FFF0F0 F0F0F0F0			897	DC	XL16' F0FFF0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
000016E8	F0F0F0F0 F0F0F0F0						
000016F0	F0F0F0F0 F0F0F0F0			898	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F292'	V3
000016F8	F0F0F0F0 F0F0F292						
				899			
00001700				900	VRI_F	VPKZR, 159, 7, 3	nv=1, p1=1 & invalid digit
00001700		00001700		901+	DS	0FD	
00001700				902+	USING	*, R5	base for test data and test routine
00001700	00001724			903+T12	DC	A(X12)	address of test routine
00001704	000C			904+	DC	H' 12'	test number
00001706	00			905+	DC	X' 00'	
00001707	9F			906+	DC	HL1' 159'	i4
00001708	07			907+	DC	HL1' 7'	m5
00001709	03			908+	DC	HL1' 3'	cc
0000170A	0E			909+	DC	HL1' 14'	cc failed mask
0000170C	00001760			910+V2_12	DC	A(RE12+16)	address of v2: 16-byte zoned decimal
00001710	00001770			911+V3_12	DC	A(RE12+32)	address of v3: 16-byte zoned decimal
00001714	E5D7D2E9 D9404040			912+	DC	CL8' VPKZR'	instruction name
0000171C	00000010			913+	DC	A(16)	result length
00001720	00001750			914+REA12	DC	A(RE12)	result address
				915+*			INSTRUCTION UNDER TEST ROUTINE
00001724				916+X12	DS	0F	
00001724	5820 500C		0000170C	917+	L	R2, V2_12	get v2
00001728	E722 0000 0006		00000000	918+	VL	V2, 0(R2)	
0000172E	5820 5010		00001710	919+	L	R2, V3_12	get v3
00001732	E732 0000 0006		00000000	920+	VL	V3, 0(R2)	
00001738	E612 3079 F070			921+	VPKZR	V1, V2, V3, 159, 7	test instruction
0000173E	E710 8F00 000E		00001100	922+	VST	V1, V10UTPUT	save result
00001744	B98D 0020			923+	EPSW	R2, R0	exptract psw
00001748	5020 8EE4		000010E4	924+	ST	R2, CCPSW	to save CC
0000174C	07FB			925+	BR	R11	return
00001750				926+RE12	DC	0F	







LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				1027			
				1028	VRI_F	VPKZR, 159, 15, 3	nsv=1, nv=1, p1=1 & invalid sign/digit
00001900				1029+	DS	0FD	
00001900		00001900		1030+	USING	*, R5	base for test data and test routine
00001900	00001924			1031+T16	DC	A(X16)	address of test routine
00001904	0010			1032+	DC	H' 16'	test number
00001906	00			1033+	DC	X' 00'	
00001907	9F			1034+	DC	HL1' 159'	i4
00001908	0F			1035+	DC	HL1' 15'	m5
00001909	03			1036+	DC	HL1' 3'	cc
0000190A	0E			1037+	DC	HL1' 14'	cc failed mask
0000190C	00001960			1038+V2_16	DC	A(RE16+16)	address of v2: 16-byte zoned decimal
00001910	00001970			1039+V3_16	DC	A(RE16+32)	address of v3: 16-byte zoned decimal
00001914	E5D7D2E9 D9404040			1040+	DC	CL8' VPKZR'	instruction name
0000191C	00000010			1041+	DC	A(16)	result length
00001920	00001950			1042+REA16	DC	A(RE16)	result address
				1043+*			INSTRUCTION UNDER TEST ROUTINE
00001924				1044+X16	DS	0F	
00001924	5820 500C		0000190C	1045+	L	R2, V2_16	get v2
00001928	E722 0000 0006		00000000	1046+	VL	V2, 0(R2)	
0000192E	5820 5010		00001910	1047+	L	R2, V3_16	get v3
00001932	E732 0000 0006		00000000	1048+	VL	V3, 0(R2)	
00001938	E612 30F9 F070			1049+	VPKZR	V1, V2, V3, 159, 15	test instruction
0000193E	E710 8F00 000E		00001100	1050+	VST	V1, V10UTPUT	save result
00001944	B98D 0020			1051+	EPSW	R2, R0	exptract psw
00001948	5020 8EE4		000010E4	1052+	ST	R2, CCPSW	to save CC
0000194C	07FB			1053+	BR	R11	return
00001950				1054+RE16	DC	0F	
00001950				1055+	DROP	R5	
00001950	F8700000 00000000			1056	DC	XL16' F8700000000000000000000000000000123F'	V1
00001958	00000000 0000123F						
00001960	F0FFF8F7 F0F0F0F0			1057	DC	XL16' F0FFF8F7F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0'	V2
00001968	F0F0F0F0 F0F0F0F0						
00001970	F0F0F0F0 F0F0F0F0			1058	DC	XL16' F0F0F0F0F0F0F0F0F0F0F0F0F0F0F0F01F293'	V3
00001978	F0F0F0F0 F0F1F293						
				1059			
00001980	00000000			1060	DC	F' 0'	END OF TABLE
00001984	00000000			1061	DC	F' 0'	
				1062 *			
				1063 *	table of pointers to individual load test		
				1064 *			
00001988				1065 E6TESTS	DS	0F	
				1066	PTTABLE		
00001988				1067+TTABLE	DS	0F	
00001988	00001180			1068+	DC	A(T1)	address of test
0000198C	00001200			1069+	DC	A(T2)	address of test
00001990	00001280			1070+	DC	A(T3)	address of test
00001994	00001300			1071+	DC	A(T4)	address of test
00001998	00001380			1072+	DC	A(T5)	address of test
0000199C	00001400			1073+	DC	A(T6)	address of test
000019A0	00001480			1074+	DC	A(T7)	address of test
000019A4	00001500			1075+	DC	A(T8)	address of test
000019A8	00001580			1076+	DC	A(T9)	address of test
000019AC	00001600			1077+	DC	A(T10)	address of test
000019B0	00001680			1078+	DC	A(T11)	address of test
000019B4	00001700			1079+	DC	A(T12)	address of test



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				1091	*****		
				1092	*		
				1093	*****		
					Register equates		
					*****		
		00000000	00000001	1095 R0	EQU	0	
		00000001	00000001	1096 R1	EQU	1	
		00000002	00000001	1097 R2	EQU	2	
		00000003	00000001	1098 R3	EQU	3	
		00000004	00000001	1099 R4	EQU	4	
		00000005	00000001	1100 R5	EQU	5	
		00000006	00000001	1101 R6	EQU	6	
		00000007	00000001	1102 R7	EQU	7	
		00000008	00000001	1103 R8	EQU	8	
		00000009	00000001	1104 R9	EQU	9	
		0000000A	00000001	1105 R10	EQU	10	
		0000000B	00000001	1106 R11	EQU	11	
		0000000C	00000001	1107 R12	EQU	12	
		0000000D	00000001	1108 R13	EQU	13	
		0000000E	00000001	1109 R14	EQU	14	
		0000000F	00000001	1110 R15	EQU	15	
				1112	*****		
				1113	*		
				1114	*****		
					Register equates		
					*****		
		00000000	00000001	1116 V0	EQU	0	
		00000001	00000001	1117 V1	EQU	1	
		00000002	00000001	1118 V2	EQU	2	
		00000003	00000001	1119 V3	EQU	3	
		00000004	00000001	1120 V4	EQU	4	
		00000005	00000001	1121 V5	EQU	5	
		00000006	00000001	1122 V6	EQU	6	
		00000007	00000001	1123 V7	EQU	7	
		00000008	00000001	1124 V8	EQU	8	
		00000009	00000001	1125 V9	EQU	9	
		0000000A	00000001	1126 V10	EQU	10	
		0000000B	00000001	1127 V11	EQU	11	
		0000000C	00000001	1128 V12	EQU	12	
		0000000D	00000001	1129 V13	EQU	13	
		0000000E	00000001	1130 V14	EQU	14	
		0000000F	00000001	1131 V15	EQU	15	
		00000010	00000001	1132 V16	EQU	16	
		00000011	00000001	1133 V17	EQU	17	
		00000012	00000001	1134 V18	EQU	18	
		00000013	00000001	1135 V19	EQU	19	
		00000014	00000001	1136 V20	EQU	20	
		00000015	00000001	1137 V21	EQU	21	













SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES													
V23	U	00000017	1	1139														
V24	U	00000018	1	1140														
V25	U	00000019	1	1141														
V26	U	0000001A	1	1142														
V27	U	0000001B	1	1143														
V28	U	0000001C	1	1144														
V29	U	0000001D	1	1145														
V2PACKED	X	0000114F	16	404														
V2VALUE	A	0000000C	4	421														
V2_1	A	0000118C	4	548	555													
V2_10	A	0000160C	4	846	853													
V2_11	A	0000168C	4	878	885													
V2_12	A	0000170C	4	910	917													
V2_13	A	0000178C	4	942	949													
V2_14	A	0000180C	4	974	981													
V2_15	A	0000188C	4	1006	1013													
V2_16	A	0000190C	4	1038	1045													
V2_2	A	0000120C	4	580	587													
V2_3	A	0000128C	4	612	619													
V2_4	A	0000130C	4	644	651													
V2_5	A	0000138C	4	676	683													
V2_6	A	0000140C	4	708	715													
V2_7	A	0000148C	4	740	747													
V2_8	A	0000150C	4	782	789													
V2_9	A	0000158C	4	814	821													
V3	U	00000003	1	1119	558	559	590	591	622	623	654	655	686	687	718	719	750	
					751	792	793	824	825	856	857	888	889	920	921	952	953	
					984	985	1016	1017	1048	1049								
V30	U	0000001E	1	1146														
V31	U	0000001F	1	1147														
V3PACKED	X	0000115F	16	405														
V3VALUE	A	00000010	4	422														
V3_1	A	00001190	4	549	557													
V3_10	A	00001610	4	847	855													
V3_11	A	00001690	4	879	887													
V3_12	A	00001710	4	911	919													
V3_13	A	00001790	4	943	951													
V3_14	A	00001810	4	975	983													
V3_15	A	00001890	4	1007	1015													
V3_16	A	00001910	4	1039	1047													
V3_2	A	00001210	4	581	589													
V3_3	A	00001290	4	613	621													
V3_4	A	00001310	4	645	653													
V3_5	A	00001390	4	677	685													
V3_6	A	00001410	4	709	717													
V3_7	A	00001490	4	741	749													
V3_8	A	00001510	4	783	791													
V3_9	A	00001590	4	815	823													
V4	U	00000004	1	1120														
V5	U	00000005	1	1121														
V6	U	00000006	1	1122														
V7	U	00000007	1	1123														
V8	U	00000008	1	1124														
V9	U	00000009	1	1125														
X1	F	000011A4	4	554	541													
X10	F	00001624	4	852	839													





DESC	SYMBOL	SIZE	POS	ADDR
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**Entry: 0**

Image	IMAGE	6616	0000- 19D7	0000- 19D7
Regi on		6616	0000- 19D7	0000- 19D7
CSECT	ZVE6TST	6616	0000- 19D7	0000- 19D7

STMT	FILE NAME
------	-----------

```
1 /devstor/dev/tests/zvector-e6-06-VPKZR.asm
```

**\*\* NO ERRORS FOUND \*\***